

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/516,377	KAWAZOE ET AL.	
Examiner		Art Unit	Paul E. Patton	
		2822	Page 1 of 1	

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,670,649 B2	12-2003	Yi et al.	257/109
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Grima-Gallardo et al., "A Comparative Study of (Cu-III-Se2)x-(FeSe)1-x Alloys (III: Al, Ga, In) (0 ≤ x ≤ 1) by X-Ray Diffraction, Differential Thermal Analysis and Scanning Electron Microscopy" Phys. Stat. Sol., 187, No 2, 395-405, Wiley, 2001. /
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.